## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10653838	CHANG ET AL.
Examiner	Art Unit
Chawan, Sheela C	2624

SEARCHED					
Class	Subclass	Date	Examiner		
382	141,199	4/12/07	SCC		
702	167	11	11		
ABOVE SEARCH UP- DATE.			11		

SEARCH NOTES				
Search Notes	Date	<b>Examiner</b> SCC		
SEARCH EAST AND OTHER DATABASE SEE ATTACHED SEARCH HISTORY.	4/12/07			
382/141,147,151,152, 203,266,190,199.CCLS. US-PATENT ONLY, SEE TEXT SEARCH.	11	11		
396/569,570.CCLS.	11	t†		
356/28,630,623,611,636,394.CCLS.	11	11		
396/569,570.CCLS.	"	ii ii		
348/139,135.CCLS.	11			
702/167.CCLS.	11	11		
INTERFERENCE SEARCH SEE SEARCH HISTORY PRINT OUT.	11	· ·		
INVENTOR NAME SEARCH.	"	"		
SEARCH IEEE OR INSPEC DATABASE.		"		
364/731 ABOLISH.	11	"		
395/133 ABOLISH.	fi fi	"		
ABOVE SEARCH UPDATE .	11	17		

INTERFERENCE SEARCH						
Class		Subclass	Date	Examiner		
382	141,199		4/12/07	SCC		
702	167		11			